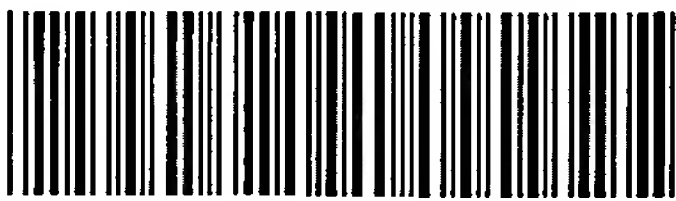


<div>Search Notes</div> <div></div>	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/726,247	AMUNDSON ET AL.	
	Examiner	Art Unit	
	Le Nguyen	2174	

SEARCHED			
Class	Subclass	Date	Examiner
715	740	1/18/2007	LVN

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
US-PGPub, USPAT: 715/740		1/18/2007	LVN

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
inventor name search	1/14/2007	LVN
US-PGPub, USPAT: 715/740,718, 771,864,963,970; 700/276-278,296, 65,83; 236/46R,47,49.1,49.3,94; 165/238,239,240,242,265,268	1/17/2007	LVN
IEEE Xplore, ACM Digital Library	1/22/2007	LVN